


<b>Search Notes</b> 	<b>Application/Control No.</b> 10527453	<b>Applicant(s)/Patent Under Reexamination</b> HANAUSKE-ABEL ET AL.
	<b>Examiner</b> MISOOK YU	<b>Art Unit</b> 1642

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
SEQ ID NO: 1 and 2, see SCORE, inventors in PALM and NPL, text searching, see the attached search history printout.	2/5/2010	MY

INTERFERENCE SEARCH			
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